INTEGRATED CIRCUITS

DATA SHEET

74F353Dual 4-input multiplexer (3-State)

Product specification

1996 Jan 05

IC15 Data Handbook





Dual 4-input multiplexer (3-State)

74F353

FEATURES

- Inverting version of 74F253
- 3-State outputs for bus interface and multiplex expansion
- Common select inputs
- Separate Output Enable Inputs

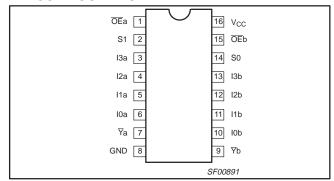
DESCRIPTION

The 74F353 has two identical 4-input multiplexers with 3-State outputs which select two bits from four sources selected by common Select inputs (S0, S1). When the individual Output Enable ($\overline{\text{OE}}$ a, $\overline{\text{OE}}$ b) inputs of the 4-input multiplexers are High, the outputs are forced to a high impedance (Hi-Z) state.

The 74F353 is the logic implementation of a 2-pole, 4-position switch; the position of the switch being determined by the logic levels supplied to the two common Select inputs.

To avoid exceeding the maximum current ratings when the outputs of the 3-State devices are tied together, all but one device must be in the high-impedance state. Therefore, only one Output Enable must be active at a time.

PIN CONFIGURATION



TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F353	6.0ns	11mA

ORDERING INFORMATION

DESCRIPTION	COMMERCIAL RANGE V_{CC} = 5V ±10%, T_{amb} = 0°C to +70°C	PACKAGE DRAWING NUMBER
16-pin plastic DIP	N74F353N	SOT38-4
16-pin plastic SO	N74F353D	SOT162-1

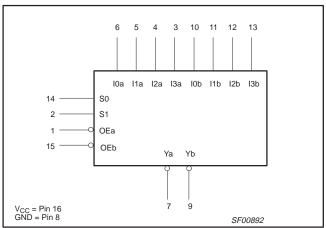
INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW		
I0a–I3a	Port A data inputs	1.0/1.0	20μA/0.6mA		
I0b-I3b	Port B data inputs	1.0/1.0	20μA/0.6mA		
S0, S1	Common Select inputs	1.0/1.0	20μA/0.6mA		
OE a	Port A Output Enable input (active Low)	1.0/1.0	20μA/0.6mA		
OE b	Port B Output Enable input (active Low)	1.0/1.0	20μA/0.6mA		
 <u></u> <u></u> <u></u> 	3-State outputs	150/40	3mA/24mA		

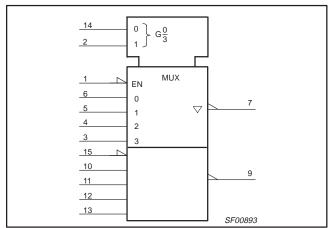
NOTE:

One (1.0) FAST unit load is defined as: 20µA in the High state and 0.6mA in the Low state.

LOGIC SYMBOL



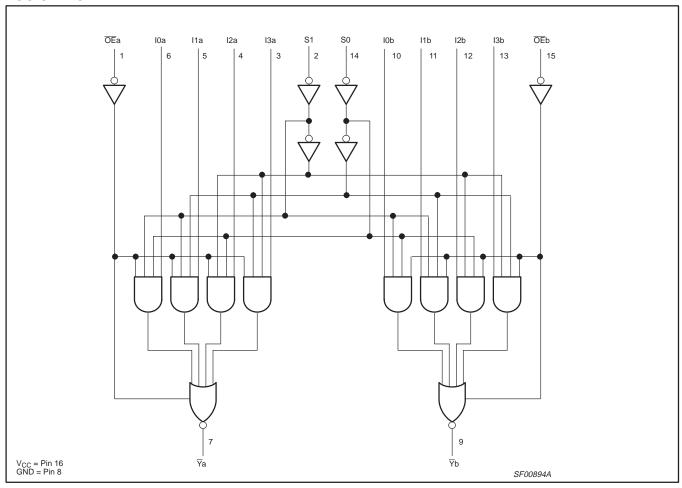
IEC/IEEE SYMBOL



Dual 4-input multiplexer (3-State)

74F353

LOGIC DIAGRAM



FUNCTION TABLE

	INPUTS										
S0	S1 I0 I1 I2 I3 \overline{OE}										
Х	Х	Х	Х	Х	Х	Н	Z				
L	L	L	Х	X	Х	L	Н				
L	L	Н	Х	Х	Х	L	L				
Н	L	X	L	Х	Х	L	Н				
Н	L	Х	Н	Х	Х	L	L				
L	н	Х	Х	L	X	L	Н				
L	н	Х	Х	Н	Х	L	L				
Н	Н	Х	Х	Х	L	L	Н				
Н	Н	Χ	Χ	Х	Н	L	L				

NOTES:

H = High voltage level
L = Low voltage level
X = Don't care
Z = High impedance "off" state

Dual 4-input multiplexer (3-State)

74F353

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limit set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage	-0.5 to +7.0	V
V _{IN}	Input voltage	-0.5 to +7.0	V
I _{IN}	Input current	−30 to +5	mA
V _{OUT}	Voltage applied to output in High output state	−0.5 to V _{CC}	V
I _{OUT}	Current applied to output in Low output state	48	mA
T _{amb}	Operating free-air temperature range	0 to +70	°C
T _{stg}	Storage temperature	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER		UNIT		
	PARAMETER	MIN	NOM	MAX	ONIT
V _{CC}	Supply voltage	4.5	5.0	5.5	V
V _{IH}	High-level input voltage	2.0			V
V _{IL}	Low-level input voltage			0.8	V
I _{IK}	Input clamp current			-18	mA
I _{OH}	High-level output current			-3	mA
I _{OL}	Low-level output current			24	mA
T _{amb}	Operating free-air temperature range	0		70	°C

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

CVMDOL	DADAMETER	TEST	TEST CONDITIONS ¹									
SYMBOL	PARAMETER	IEST	TEST CONDITIONS			TYP ²	MAX	UNIT				
M	I limb loved autout valence		V _{CC} = MIN, V _{IL} = I	MAX,	±10%V _{CC}	2.4			V			
V _{OH}	High-level output voltage		$V_{IH} = MIN, I_{OH} = N$	MAX	±5%V _{CC}	2.7	3.3		V			
V	I am laval autout valta sa		V _{CC} = MIN, V _{IL} = I	MAX,	±10%V _{CC}		0.35	0.50	V			
V _{OL}	Low-level output voltage		$V_{IH} = MIN, I_{OL} = N$	$V_{IH} = MIN, I_{OL} = MAX$			0.35	0.50	V			
V _{IK}	Input clamp voltage		$V_{CC} = MIN, I_I = I_{IK}$				-0.73	-1.2	V			
l _l	Input current at maximum inp	t current at maximum input voltage		$V_{CC} = MAX, V_I = 7.0V$			V _I = 7.0V				100	μΑ
I _{IH}	High-level input current	$V_{CC} = MAX, V_I = 2.7V$					20	μΑ				
I _{IL}	Low-level input current		$V_{CC} = MAX, V_I = 0.5V$					-0.6	mA			
l _{OZH}	Off-state output current High-level voltage applied		V _{CC} = MAX, V _O =	$V_{CC} = MAX, V_O = 2.7V$				50	μА			
I _{OZL}	Off-state output current Low-level voltage applied		$V_{CC} = MAX, V_{O} = 0$	$V_{CC} = MAX, V_O = 0.5V$				-50	μА			
los	Short-circuit output current ³		V _{CC} = MAX	V _{CC} = MAX				-150	mA			
		I _{CCH}		OEn=Sn=In=	=GND		9	14	mA			
I _{CC}	Supply current (total) I _{CCL}		V _{CC} = MAX		OEn=Sn=GND, In=4.5V		11	20	mA			
			OEn=4.5V, Sn=In=GND				13	23	mA			

NOTES:

- 1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- 2. All typical values are at V_{CC} = 5V, T_{amb} = 25°C.

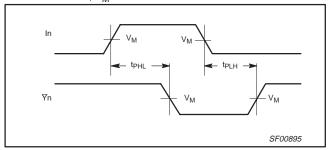
^{3.} Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

AC ELECTRICAL CHARACTERISTICS

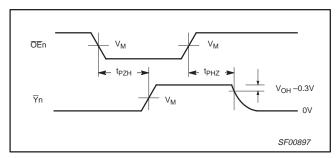
SYMBOL	PARAMETER	TEST CONDITION	T _i C _L = \$	V _{CC} = 5V _{amb} = +25° 50pF, R _L =	°C 500Ω	V _{CC} = 5 T _{amb} = 0°0 C _L = 50pF,	UNIT	
			MIN	TYP	MAX	MIN	MAX	
t _{PLH}	Propagation delay In to Yn	Waveform 1	3.0 1.5	5.0 3.0	7.0 5.0	3.0 1.0	8.0 5.5	ns
t _{PLH} t _{PHL}	Propagation delay Sn to Yn	Waveform 2	5.0 3.0	9.0 6.0	12.0 8.5	4.5 3.0	12.5 9.5	ns
t _{PZH}	Output Enable time to High or Low level	Waveform 3 Waveform 4	4.0 4.0	6.0 6.5	8.0 8.0	3.5 3.5	9.0 9.0	ns
t _{PHZ}	Output Disable time from High or Low level	Waveform 3 Waveform 4	2.5 1.5	4.0 2.5	5.5 6.0	2.0 1.5	6.0 7.0	ns

AC WAVEFORMS

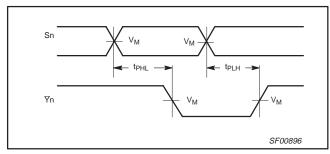
For all waveforms, $V_M = 1.5V$



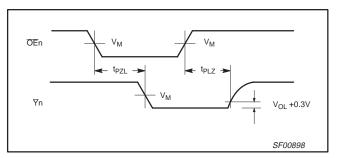
Waveform 1. Propagation Delay, Data to Output



Waveform 3. 3-State Output Enable Time to High Level and Output Disable Time from High Level



Waveform 2. Propagation Delay, Select to Output



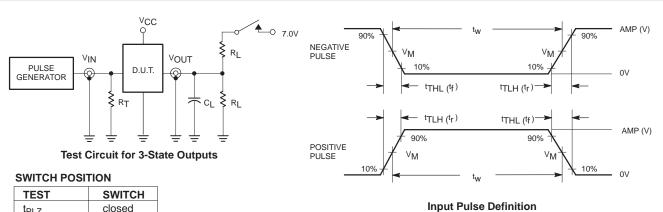
Waveform 4. 3-State Output Enable Time to Low Level and Output Disable Time from Low Level

1996 Jan 05 5

Dual 4-input multiplexer (3-State)

74F353

TEST CIRCUIT AND WAVEFORMS



SWITCH
closed
closed
open

DEFINITIONS:

 R_L = Load resistor;

see AC electrical characteristics for value.
Load capacitance includes jig and probe capacitance; see AC electrical characteristics for value.

Termination resistance should be equal to $Z_{\mbox{\scriptsize OUT}}$ of pulse generators.

family	TS								
family	amplitude V _M rep. rate t _w t _{TLH} t _{THL}								
74F	3.0V	1.5V	1MHz	500ns	2.5ns	2.5ns			

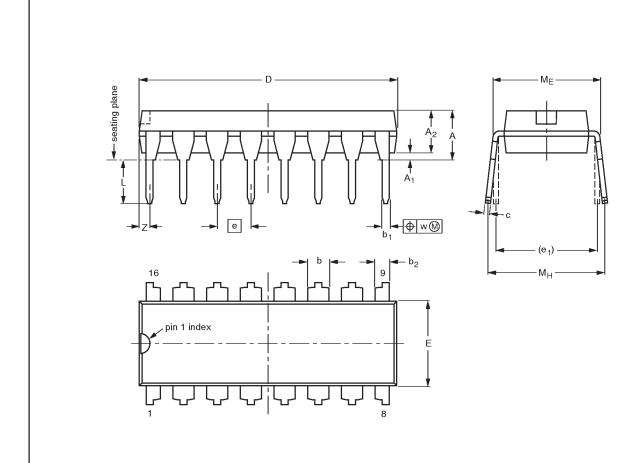
SF00777

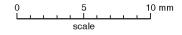
Dual 4-input multiplexer (3-State)

74F353

DIP16: plastic dual in-line package; 16 leads (300 mil)

SOT38-4





DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	b ₂	c	D ⁽¹⁾	E ⁽¹⁾	е	e ₁	L	ME	Мн	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	1.25 0.85	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	0.76
inches	0.17	0.020	0.13	0.068 0.051	0.021 0.015	0.049 0.033	0.014 0.009	0.77 0.73	0.26 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.030

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	RENCES	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE	
SOT38-4					92-11-17 95-01-14	

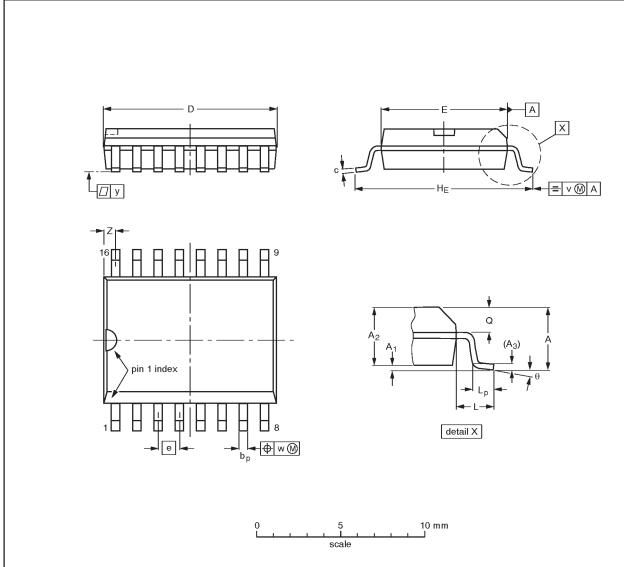
1996 Jan 05 7

Dual 4-input multiplexer (3-State)

74F353

SO16: plastic small outline package; 16 leads; body width 7.5 mm

SOT162-1



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	Α1	A ₂	A ₃	рb	С	D ⁽¹⁾	E ⁽¹⁾	е	HE	L	Lp	Ø	v	w	у	z ⁽¹⁾	θ
mm	2.65	0.30 0.10	2.45 2.25	0.25	0.49 0.36	0.32 0.23	10.5 10.1	7.6 7.4	1.27	10.65 10.00	1.4	1.1 0.4	1.1 1.0	0.25	0.25	0.1	0.9 0.4	8°
inches	0.10	0.012 0.004	0.096 0.089	0.01	0.019 0.014	0.013 0.009	0.41 0.40	0.30 0.29	0.050	0.42 0.39	0.055	0.043 0.016		0.01	0.01	0.004	0.035 0.016	0°

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT162-1	075E03	MS-013AA				-92-11-17 95-01-24

Dual 4-input multiplexer (3-State)

74F353

NOTES

Dual 4-input multiplexer (3-State)

74F353

Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

^[1] Please consult the most recently issued datasheet before initiating or completing a design.

Definitions

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

Application information — Applications that are described herein for any of these products are for illustrative purposes only. Philips Semiconductors make no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Disclaimers

Life support — These products are not designed for use in life support appliances, devices or systems where malfunction of these products can reasonably be expected to result in personal injury. Philips Semiconductors customers using or selling these products for use in such applications do so at their own risk and agree to fully indemnify Philips Semiconductors for any damages resulting from such application.

Right to make changes — Philips Semiconductors reserves the right to make changes, without notice, in the products, including circuits, standard cells, and/or software, described or contained herein in order to improve design and/or performance. Philips Semiconductors assumes no responsibility or liability for the use of any of these products, conveys no license or title under any patent, copyright, or mask work right to these products, and makes no representations or warranties that these products are free from patent, copyright, or mask work right infringement, unless otherwise specified.

Philips Semiconductors 811 East Arques Avenue P.O. Box 3409 Sunnyvale, California 94088–3409 Telephone 800-234-7381 © Copyright Philips Electronics North America Corporation 1998 All rights reserved. Printed in U.S.A.

Date of release: 03-98

Document order number: 9397 750 03684

Let's make things better.

Philips Semiconductors





This datasheet has been download from:

www.datasheetcatalog.com

Datasheets for electronics components.